

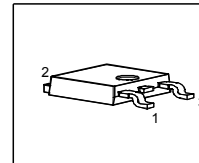
## Cool MOS™ Power Transistor

### Feature

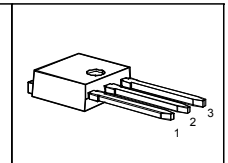
- New revolutionary high voltage technology
- Ultra low gate charge
- Periodic avalanche rated
- Extreme  $dv/dt$  rated
- Ultra low effective capacitances
- Improved transconductance

|              |      |          |
|--------------|------|----------|
| $V_{DS}$     | 600  | V        |
| $R_{DS(on)}$ | 0.95 | $\Omega$ |
| $I_D$        | 4.5  | A        |

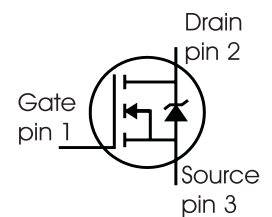
P-TO252.



P-TO251.



| Type       | Package  | Ordering Code | Marking |
|------------|----------|---------------|---------|
| SPU04N60S5 | P-TO251. | Q67040-S4228  | 04N60S5 |
| SPD04N60S5 | P-TO252. | Q67040-S4202  | 04N60S5 |



### Maximum Ratings

| Parameter   | Symbol             | Value       | Unit             |
|---|--------------------|-------------|------------------|
| Continuous drain current<br>$T_C = 25\text{ }^\circ\text{C}$<br>$T_C = 100\text{ }^\circ\text{C}$                         | $I_D$              | 4.5<br>2.8  | A                |
| Pulsed drain current, $t_p$ limited by $T_{jmax}$   | $I_D \text{ puls}$ | 9           |                  |
| Avalanche energy, single pulse<br>$I_D = 3.4\text{ A}$ , $V_{DD} = 50\text{ V}$   | $E_{AS}$           | 130         | mJ               |
| Avalanche energy, repetitive $t_{AR}$ limited by $T_{jmax}$ <sup>1</sup><br>$I_D = 4.5\text{ A}$ , $V_{DD} = 50\text{ V}$ | $E_{AR}$           | 0.4         |                  |
| Avalanche current, repetitive $t_{AR}$ limited by $T_{jmax}$  | $I_{AR}$           | 4.5         | A                |
| Gate source voltage   | $V_{GS}$           | $\pm 20$    | V                |
| Gate source voltage AC ( $f > 1\text{ Hz}$ )  | $V_{GS}$           | $\pm 30$    |                  |
| Power dissipation, $T_C = 25\text{ }^\circ\text{C}$   | $P_{tot}$          | 50          | W                |
| Operating and storage temperature   | $T_j, T_{stg}$     | -55... +150 | $^\circ\text{C}$ |

**Maximum Ratings**

| Parameter  | Symbol  | Value | Unit |
|--|---------|-------|------|
| Drain Source voltage slope<br>$V_{DS} = 480\text{ V}$ , $I_D = 4.5\text{ A}$ , $T_j = 125\text{ °C}$ | $dv/dt$ | 20    | V/ns |

**Thermal Characteristics**

| Parameter   | Symbol     | Values |      |      | Unit |
|---|------------|--------|------|------|------|
|   |            | min.   | typ. | max. |      |
| Thermal resistance, junction - case   | $R_{thJC}$ | -      | -    | 2.5  | K/W  |
| Thermal resistance, junction - ambient, leaded  | $R_{thJA}$ | -      | -    | 62   |      |
| SMD version, device on PCB:<br>@ min. footprint<br>@ 6 cm <sup>2</sup> cooling area <sup>2)</sup> | $R_{thJA}$ | -      | -    | 62   |      |
| Soldering temperature,<br>1.6 mm (0.063 in.) from case for 10s                                    | $T_{sold}$ | -      | -    | 260  | °C   |

**Electrical Characteristics, at  $T_j=25\text{ °C}$  unless otherwise specified**

| Parameter                                   | Symbol        | Conditions   | Values |      |      | Unit     |
|---|---------------|--|--------|------|------|----------|
|   |               |  | min.   | typ. | max. |          |
| Drain-source breakdown voltage              | $V_{(BR)DSS}$ | $V_{GS}=0V$ , $I_D=0.25mA$   | 600    | -    | -    | V        |
| Drain-Source avalanche<br>breakdown voltage | $V_{(BR)DS}$  | $V_{GS}=0V$ , $I_D=4.5A$   | -      | 700  | -    |          |
| Gate threshold voltage                      | $V_{GS(th)}$  | $I_D=200\mu A$ , $V_{GS}=V_{DS}$   | 3.5    | 4.5  | 5.5  |          |
| Zero gate voltage drain current             | $I_{DSS}$     | $V_{DS}=600V$ , $V_{GS}=0V$ ,<br>$T_j=25\text{ °C}$ ,<br>$T_j=150\text{ °C}$ | -      | 0.5  | 1    | $\mu A$  |
| Gate-source leakage current                 | $I_{GSS}$     | $V_{GS}=20V$ , $V_{DS}=0V$   | -      | -    | 100  |          |
| Drain-source on-state resistance            | $R_{DS(on)}$  | $V_{GS}=10V$ , $I_D=2.8A$ ,<br>$T_j=25\text{ °C}$<br>$T_j=150\text{ °C}$     | -      | 0.85 | 0.95 | $\Omega$ |
| Gate input resistance                       | $R_G$         | $f=1MHz$ , open Drain  | -      | 20   | -    |          |

**Electrical Characteristics** , at  $T_j = 25\text{ }^\circ\text{C}$ , unless otherwise specified

| Parameter   | Symbol       | Conditions   | Values |      |      | Unit |
|---|--------------|--|--------|------|------|------|
|   |              |  | min.   | typ. | max. |      |
| <b>Characteristics</b>  |              |  |        |      |      |      |
| Transconductance  | $g_{fs}$     | $V_{DS} \geq 2 \cdot I_D \cdot R_{DS(on)max}$ ,<br>$I_D = 2.8\text{A}$                       | -      | 2.5  | -    | S    |
| Input capacitance   | $C_{iss}$    | $V_{GS} = 0\text{V}$ , $V_{DS} = 25\text{V}$ ,   | -      | 580  | -    | pF   |
| Output capacitance  | $C_{oss}$    | $f = 1\text{MHz}$  | -      | 220  | -    |      |
| Reverse transfer capacitance                                  | $C_{rss}$    |  | -      | 7    | -    |      |
| Effective output capacitance, <sup>3)</sup><br>energy related | $C_{o(er)}$  | $V_{GS} = 0\text{V}$ ,<br>$V_{DS} = 0\text{V to } 480\text{V}$                               | -      | 20   | -    | pF   |
| Effective output capacitance, <sup>4)</sup><br>time related   | $C_{o(tr)}$  |  | -      | 35   | -    |      |
| Turn-on delay time  | $t_{d(on)}$  | $V_{DD} = 350\text{V}$ , $V_{GS} = 0/10\text{V}$ ,<br>$I_D = 4.5\text{A}$ , $R_G = 18\Omega$ | -      | 55   | -    | ns   |
| Rise time   | $t_r$        | $V_{DD} = 350\text{V}$ , $V_{GS} = 0/10\text{V}$ ,<br>$I_D = 4.5\text{A}$ , $R_G = 18$       | -      | 30   | -    |      |
| Turn-off delay time   | $t_{d(off)}$ | $V_{DD} = 350\text{V}$ , $V_{GS} = 0/10\text{V}$ ,   | -      | 60   | 90   |      |
| Fall time   | $t_f$        | $I_D = 4.5\text{A}$ , $R_G = 18\Omega$   | -      | 15   | 22.5 |      |

**Gate Charge Characteristics**

|                       |                 |  |   |      |      |    |
|-----------------------|-----------------|--|---|------|------|----|
| Gate to source charge | $Q_{gs}$        | $V_{DD} = 350\text{V}$ , $I_D = 4.5\text{A}$   | - | 4.5  | -    | nC |
| Gate to drain charge  | $Q_{gd}$        |  | - | 11   | -    |    |
| Gate charge total     | $Q_g$           | $V_{DD} = 350\text{V}$ , $I_D = 4.5\text{A}$ ,<br>$V_{GS} = 0\text{ to } 10\text{V}$ | - | 17.6 | 22.9 |    |
| Gate plateau voltage  | $V_{(plateau)}$ | $V_{DD} = 350\text{V}$ , $I_D = 4.5\text{A}$   | - | 8    | -    | V  |

<sup>1</sup> Repetitive avalanche causes additional power losses that can be calculated as  $P_{AV} = E_{AR} \cdot f$ .

<sup>2</sup> Device on 40mm\*40mm\*1.5mm epoxy PCB FR4 with 6cm<sup>2</sup> (one layer, 70 μm thick) copper area for drain connection. PCB is vertical without blown air.

<sup>3</sup>  $C_{o(er)}$  is a fixed capacitance that gives the same stored energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 80%  $V_{DSS}$ .

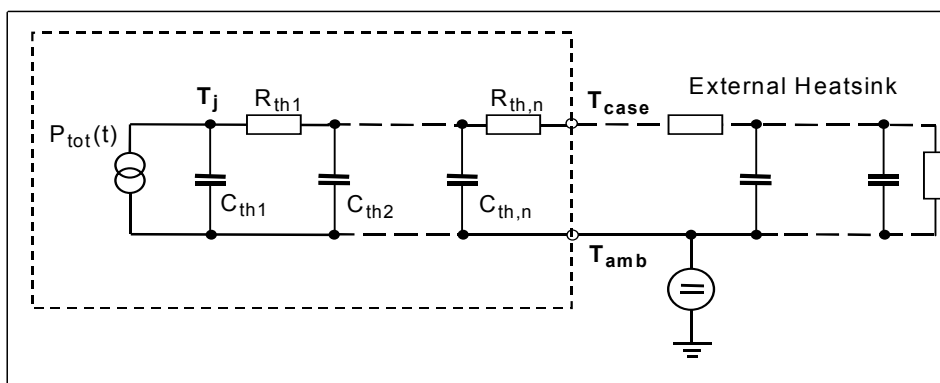
<sup>4</sup>  $C_{o(tr)}$  is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 80%  $V_{DSS}$ .

**Electrical Characteristics**, at  $T_j = 25\text{ }^\circ\text{C}$ , unless otherwise specified

| Parameter                                | Symbol   | Conditions                        | Values |      |      | Unit          |
|--|----------|-----------------------------------|--------|------|------|---------------|
|  |          |                                   | min.   | typ. | max. |               |
| Inverse diode continuous forward current | $I_S$    | $T_C=25^\circ\text{C}$            | -      | -    | 4.5  | A             |
| Inverse diode direct current, pulsed     | $I_{SM}$ |                                   | -      | -    | 9    |               |
| Inverse diode forward voltage            | $V_{SD}$ | $V_{GS}=0\text{V}, I_F=I_S$       | -      | 1    | 1.2  | V             |
| Reverse recovery time                    | $t_{rr}$ | $V_R=350\text{V}, I_F=I_S,$       | -      | 900  | 1530 | ns            |
| Reverse recovery charge                  | $Q_{rr}$ | $di_F/dt=100\text{A}/\mu\text{s}$ | -      | 3.2  | -    | $\mu\text{C}$ |

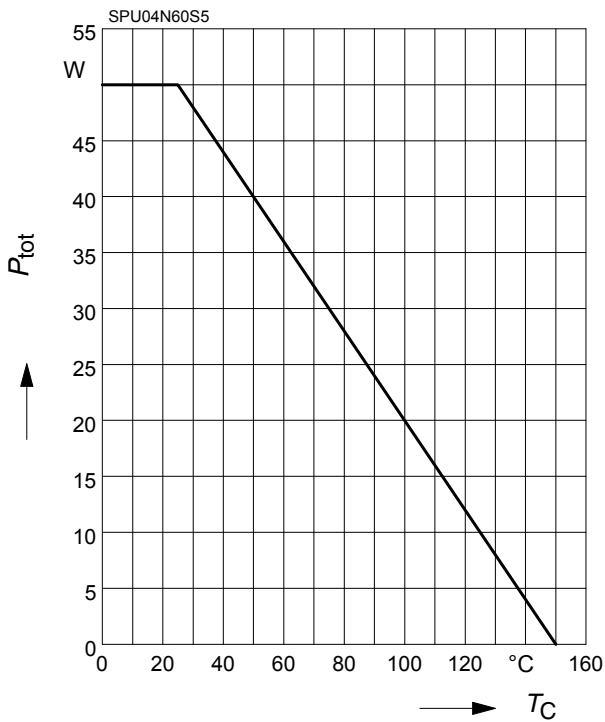
**Typical Transient Thermal Characteristics**

| Symbol             | Value | Unit | Symbol              | Value      | Unit |
|--------------------|-------|------|---------------------|------------|------|
|                    | typ.  |      |                     | typ.       |      |
| Thermal resistance |       |      | Thermal capacitance |            |      |
| $R_{th1}$          | 0.039 | K/W  | $C_{th1}$           | 0.00007347 | Ws/K |
| $R_{th2}$          | 0.074 |      | $C_{th2}$           | 0.0002831  |      |
| $R_{th3}$          | 0.132 |      | $C_{th3}$           | 0.0004062  |      |
| $R_{th4}$          | 0.555 |      | $C_{th4}$           | 0.001215   |      |
| $R_{th5}$          | 0.529 |      | $C_{th5}$           | 0.00276    |      |
| $R_{th6}$          | 0.169 |      | $C_{th6}$           | 0.029      |      |



**1 Power dissipation**

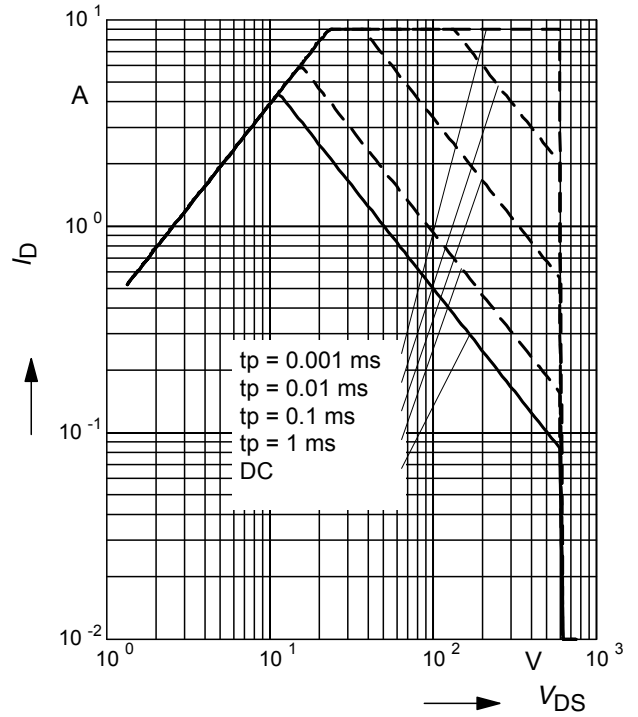
$P_{tot} = f(T_C)$



**2 Safe operating area**

$I_D = f(V_{DS})$

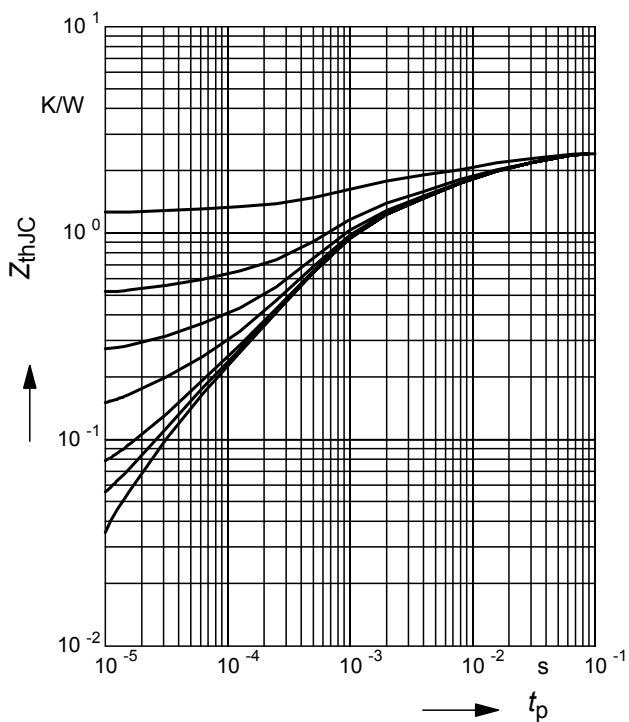
parameter :  $D = 0$  ,  $T_C = 25^\circ C$



**3 Transient thermal impedance**

$Z_{thJC} = f(t_p)$

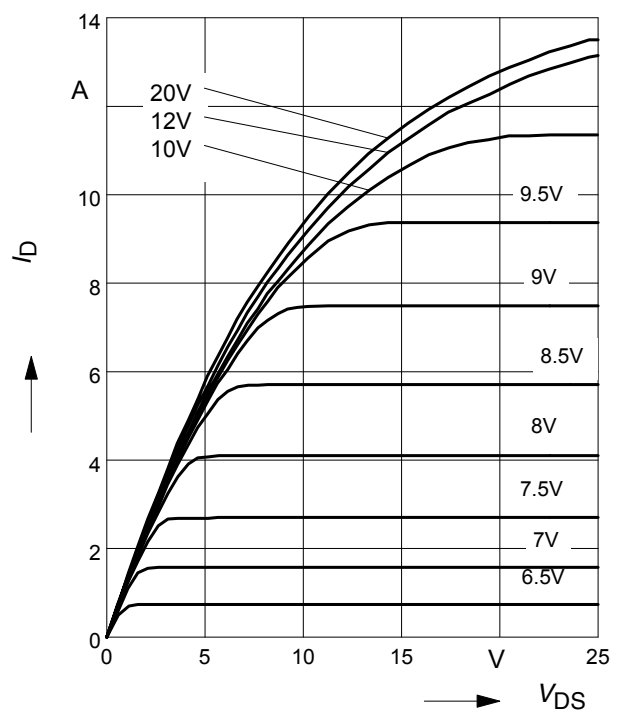
parameter:  $D = t_p/T$



**4 Typ. output characteristic**

$I_D = f(V_{DS})$ ;  $T_j = 25^\circ C$

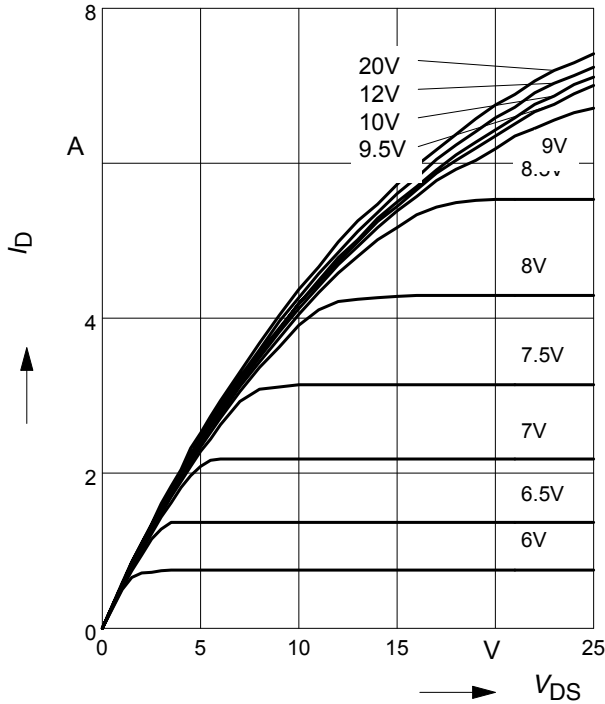
parameter:  $t_p = 10 \mu s$ ,  $V_{GS}$



**5 Typ. output characteristic**

$I_D = f(V_{DS}); T_j = 150^\circ\text{C}$

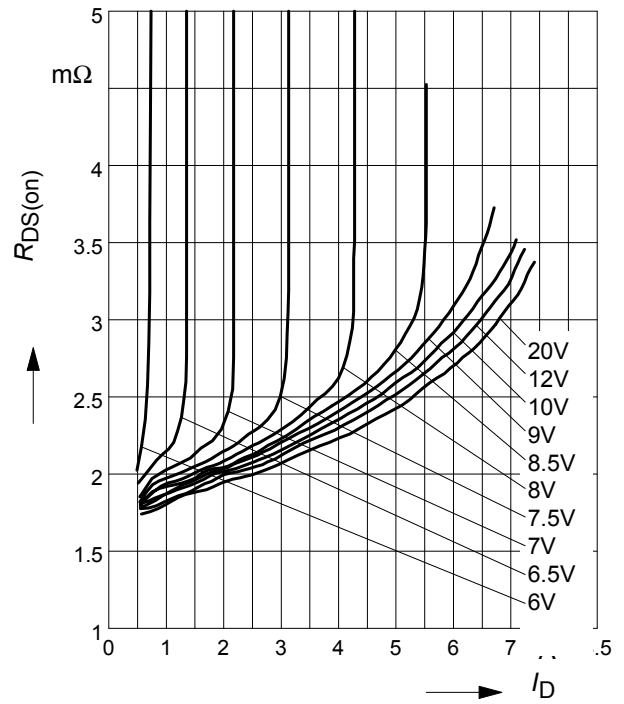
parameter:  $t_p = 10 \mu\text{s}, V_{GS}$



**6 Typ. drain-source on resistance**

$R_{DS(on)} = f(I_D)$

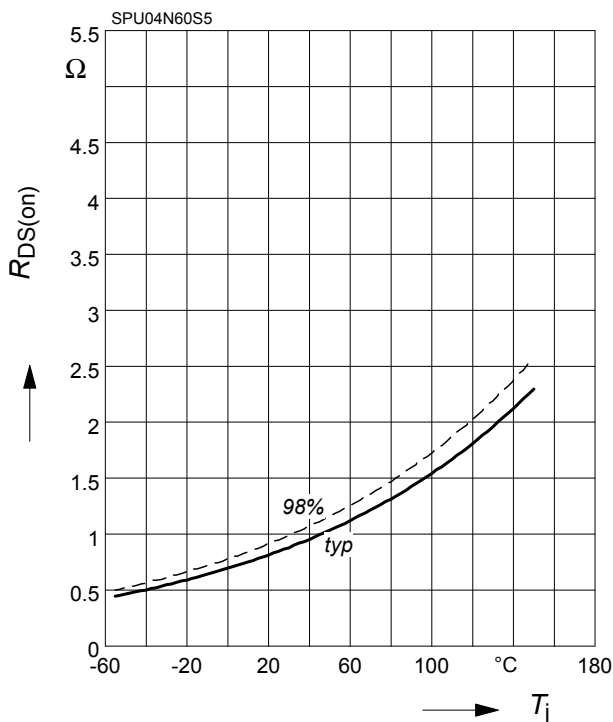
parameter:  $T_j = 150^\circ\text{C}, V_{GS}$



**7 Drain-source on-state resistance**

$R_{DS(on)} = f(T_j)$

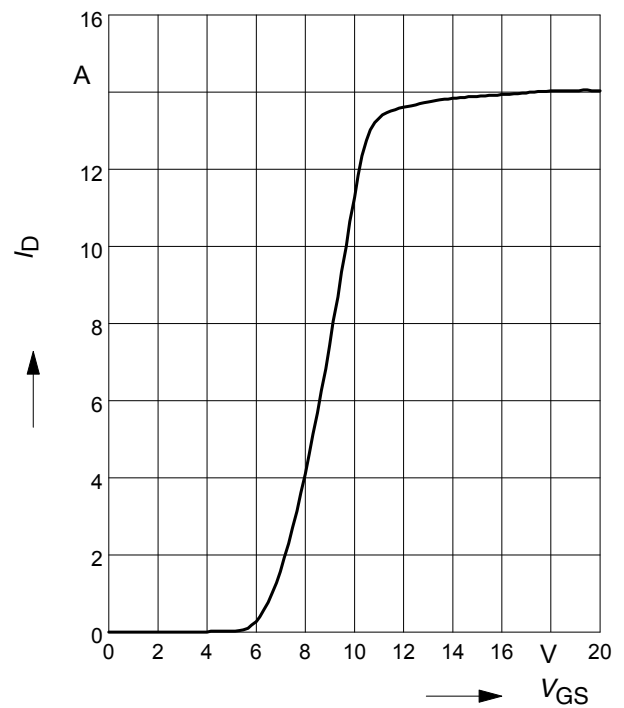
parameter:  $I_D = 2.8 \text{ A}, V_{GS} = 10 \text{ V}$



**8 Typ. transfer characteristics**

$I_D = f(V_{GS}); V_{DS} \geq 2 \times I_D \times R_{DS(on)max}$

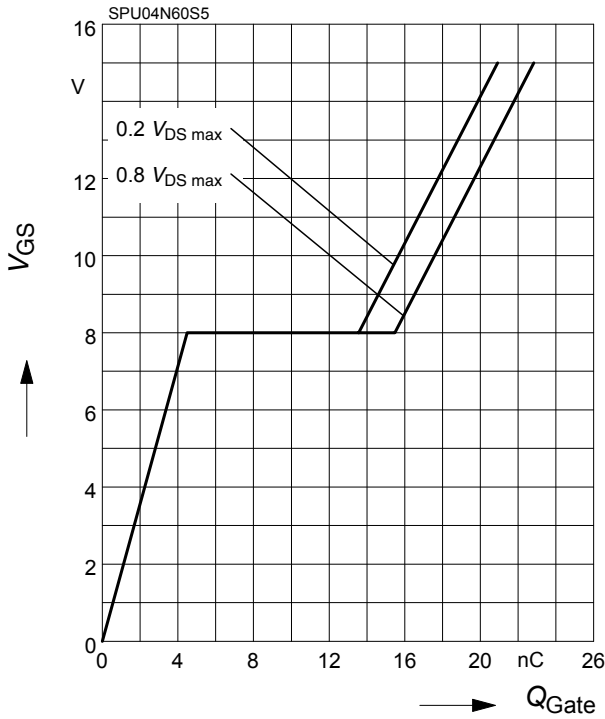
parameter:  $t_p = 10 \mu\text{s}$



**9 Typ. gate charge**

$V_{GS} = f(Q_{Gate})$

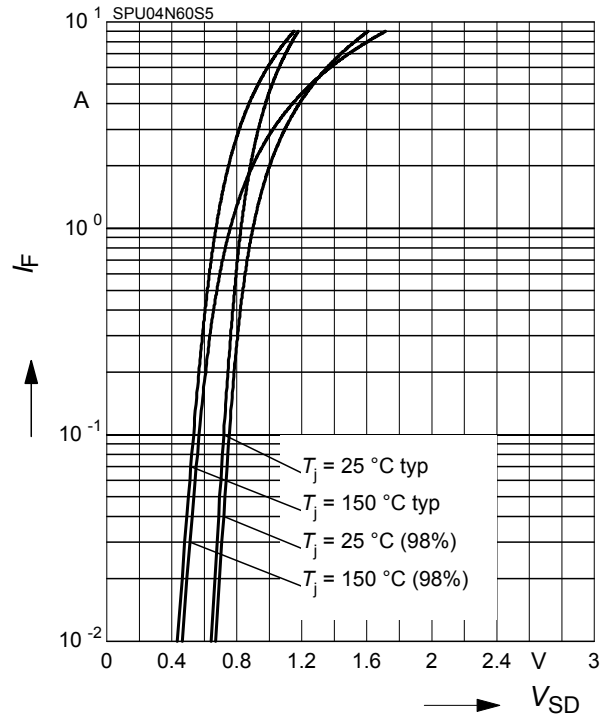
parameter:  $I_D = 4.5$  A pulsed



**10 Forward characteristics of body diode**

$I_F = f(V_{SD})$

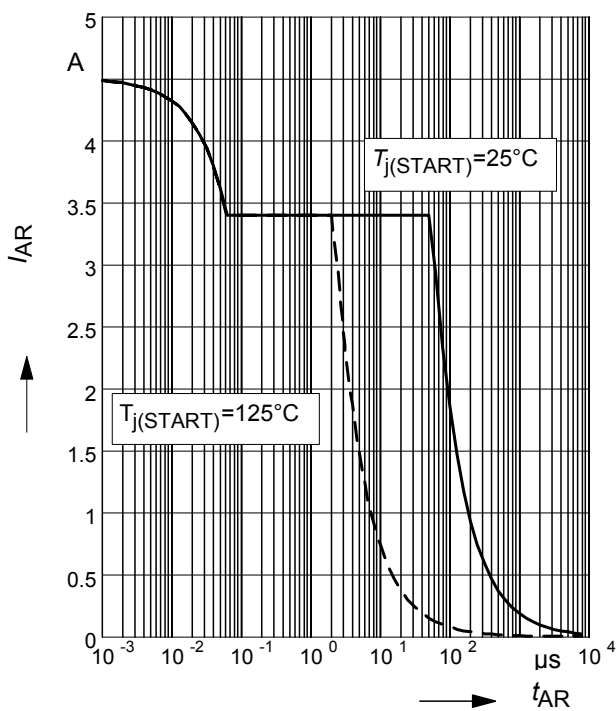
parameter:  $T_j$ ,  $t_p = 10$   $\mu$ s



**11 Avalanche SOA**

$I_{AR} = f(t_{AR})$

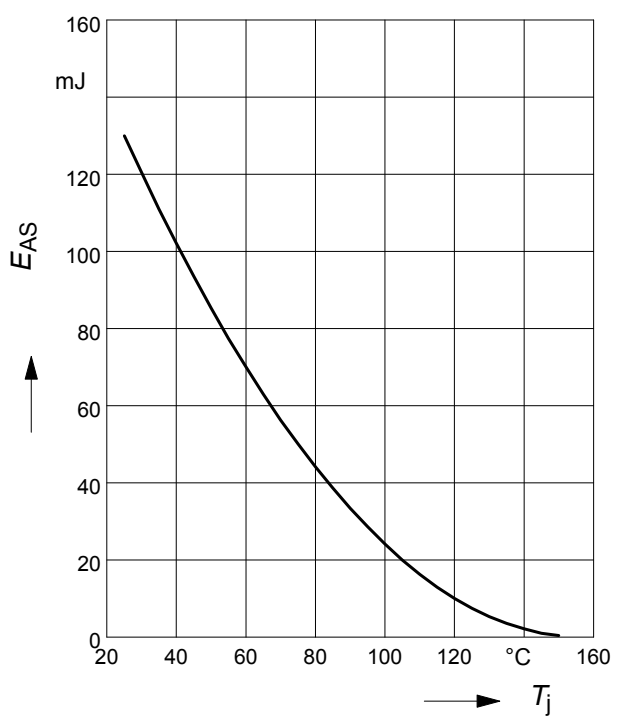
par.:  $T_j \leq 150$  °C



**12 Avalanche energy**

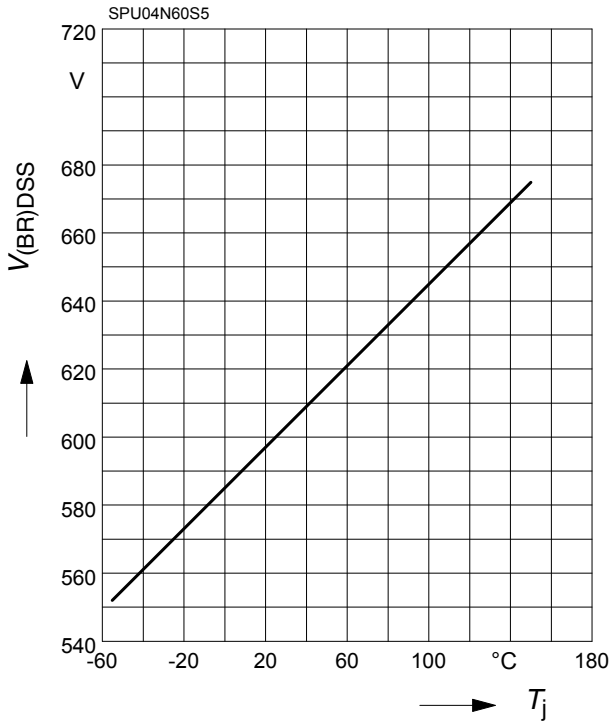
$E_{AS} = f(T_j)$

par.:  $I_D = 3.4$  A,  $V_{DD} = 50$  V



**13 Drain-source breakdown voltage**

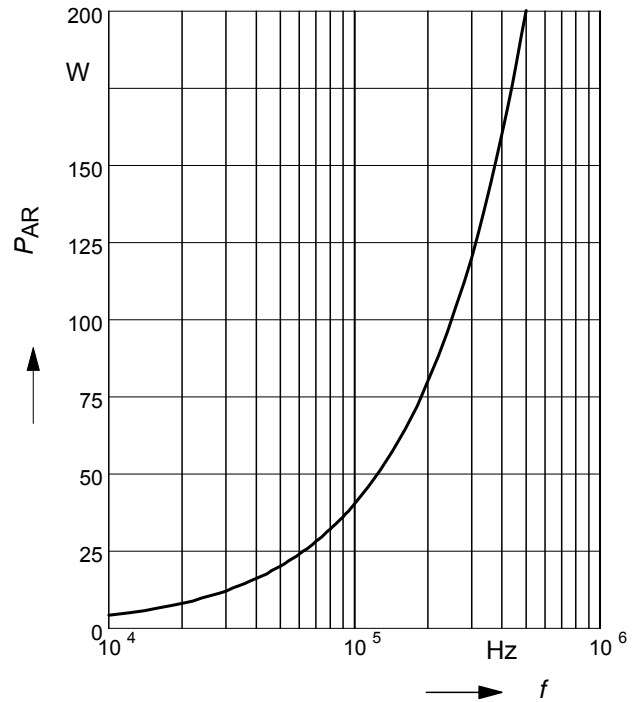
$$V_{(BR)DSS} = f(T_j)$$



**14 Avalanche power losses**

$$P_{AR} = f(f)$$

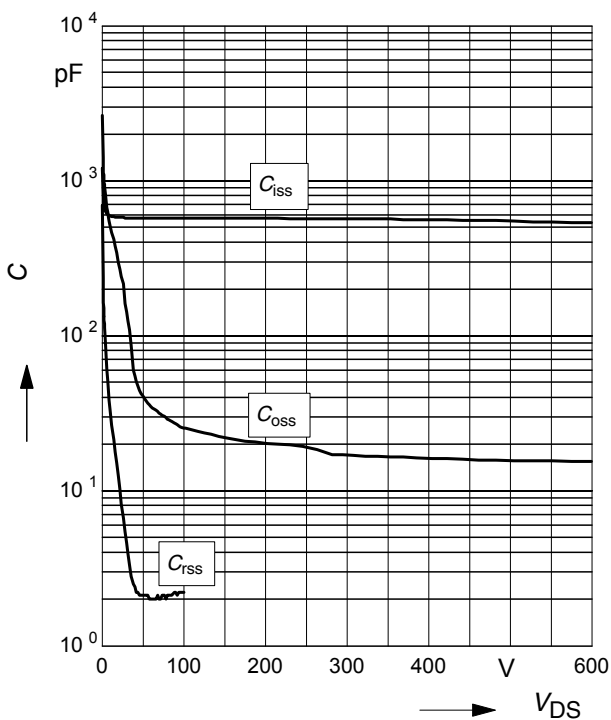
parameter:  $E_{AR}=0.4\text{mJ}$



**15 Typ. capacitances**

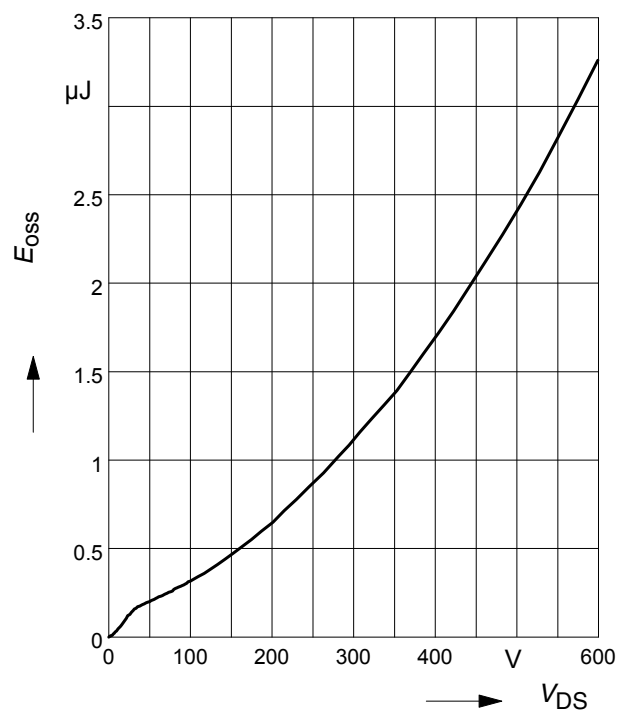
$$C = f(V_{DS})$$

parameter:  $V_{GS}=0\text{V}$ ,  $f=1\text{ MHz}$



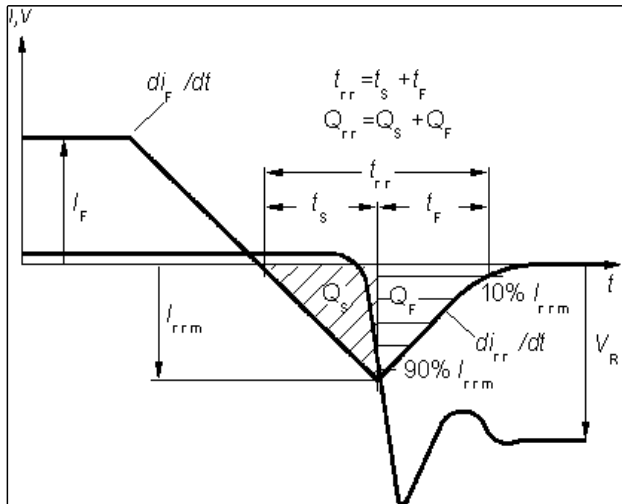
**16 Typ.  $C_{OSS}$  stored energy**

$$E_{OSS} = f(V_{DS})$$

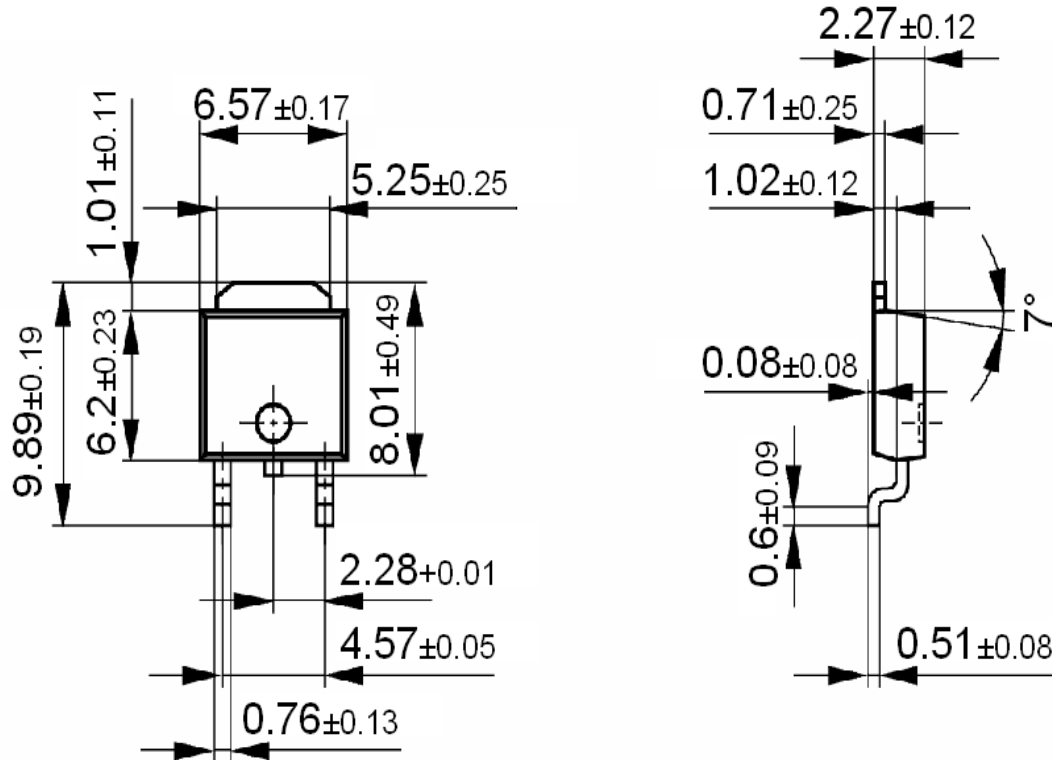




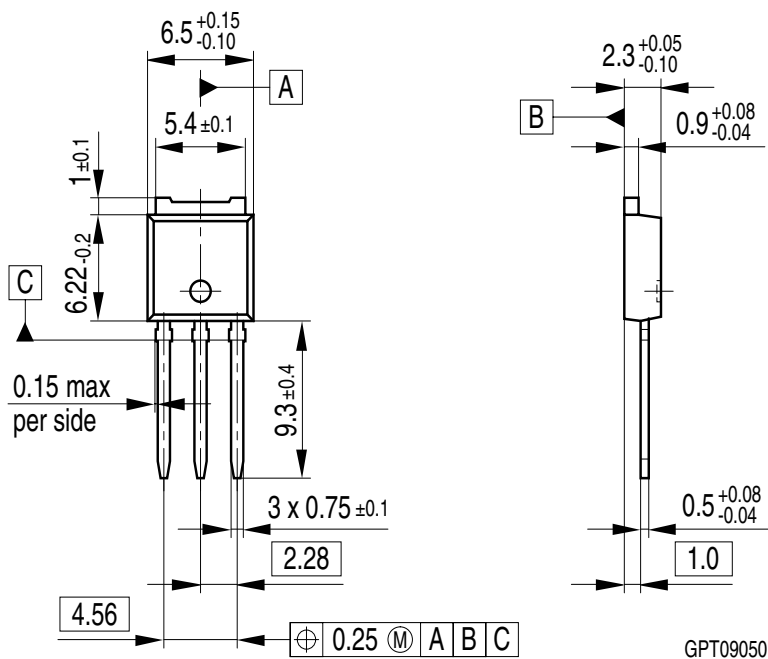
Definition of diodes switching characteristics



P-TO-252-3-1 (D-PAK)



P-TO-251-3-1 (I-PAK)



All metal surfaces tin plated, except area of cut.

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